

A decorative graphic on the left side of the slide, consisting of a series of overlapping, colorful, diamond-shaped patterns that create a sense of depth and movement, resembling a stylized lens or a series of overlapping planes.

E-Beam Lithography Stencil Planning and Optimization With Overlapped Characters

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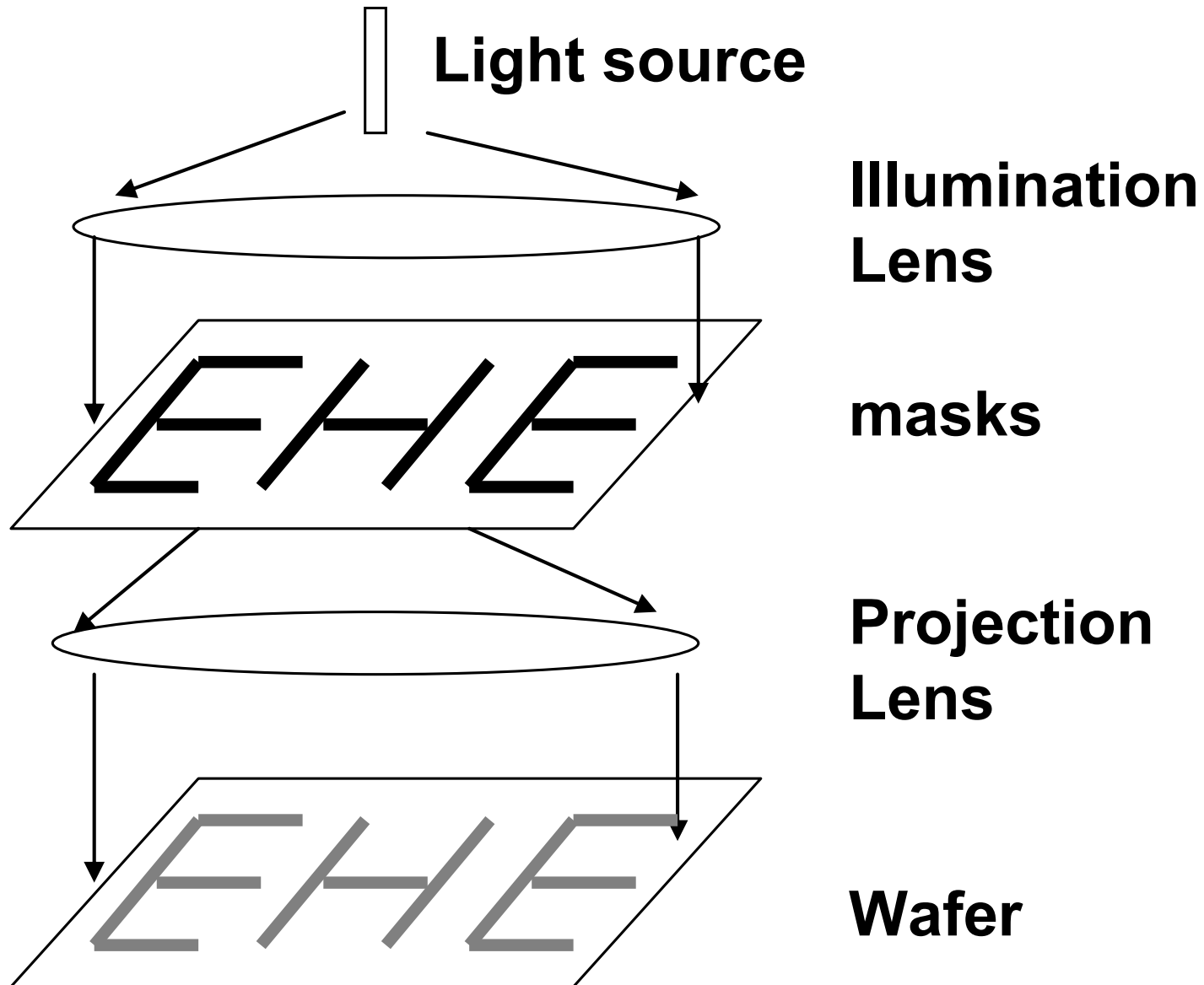
The University of Texas at Austin

<http://www.cerc.utexas.edu/utda>

Outline

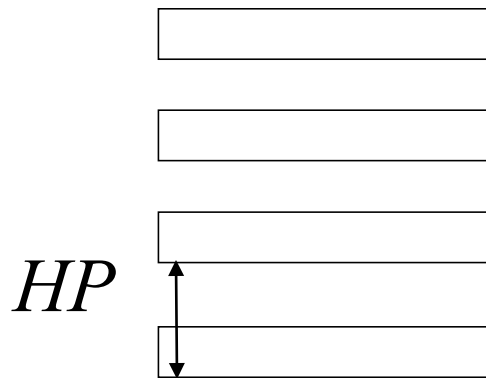
- ◆ Introduction and Motivation
 - › Electronic Beam Lithography (EBL)
 - › Overlapped Characters
- ◆ EBL Stencil Planning/Optimization
 - › One-Dimensional Stencil Design
 - › Two-Dimensional Stencil Design
- ◆ Experimental Results
- ◆ Conclusion

Conventional Optical Lithography



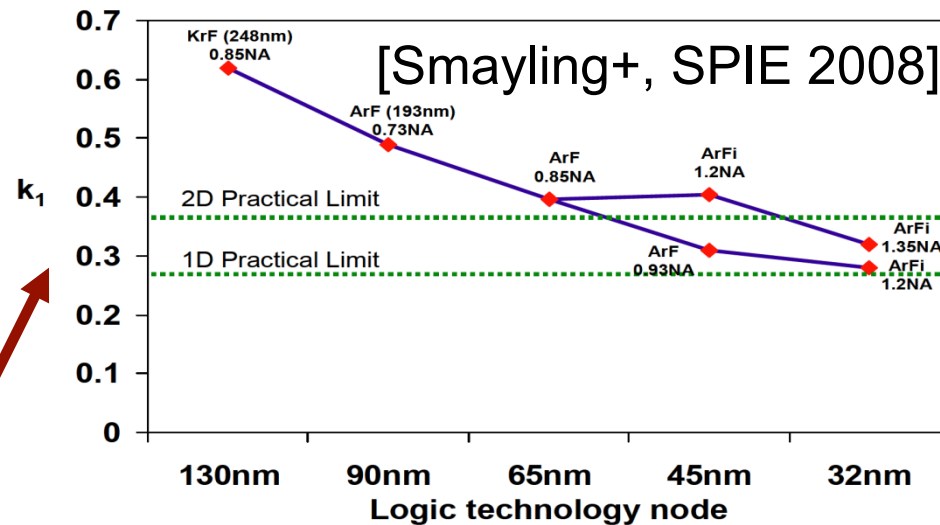
Scaling Woos

◆ Aggressive scaling of min. printable half pitch HP



$$HP = k_1 \frac{\lambda}{NA}$$

k_1 : process difficulty
NA: numerical aperture
 λ : wavelength of source



◆ λ is stuck at 193nm

◆ k_1 : limit is 0.25

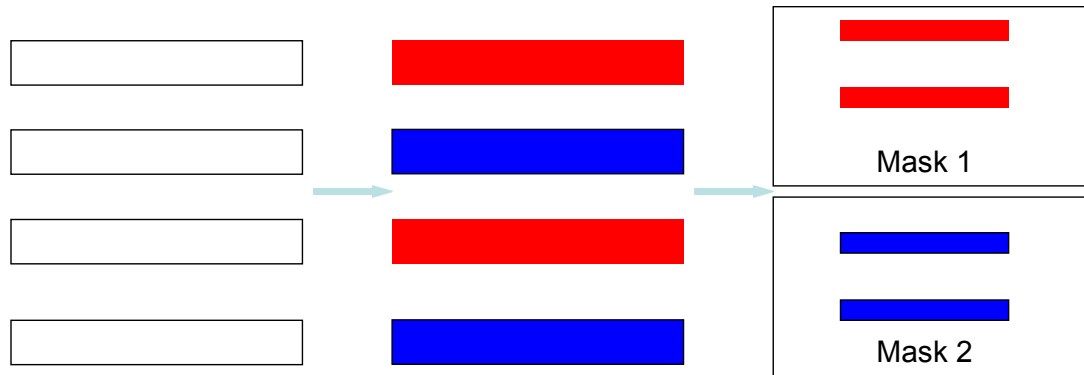
◆ NA = 1.5, close to the limit

◆ EUV (13.5nm): Still many, many challenges!

Mask Cost !!!



Alternative solution for 32nm/22nm and below



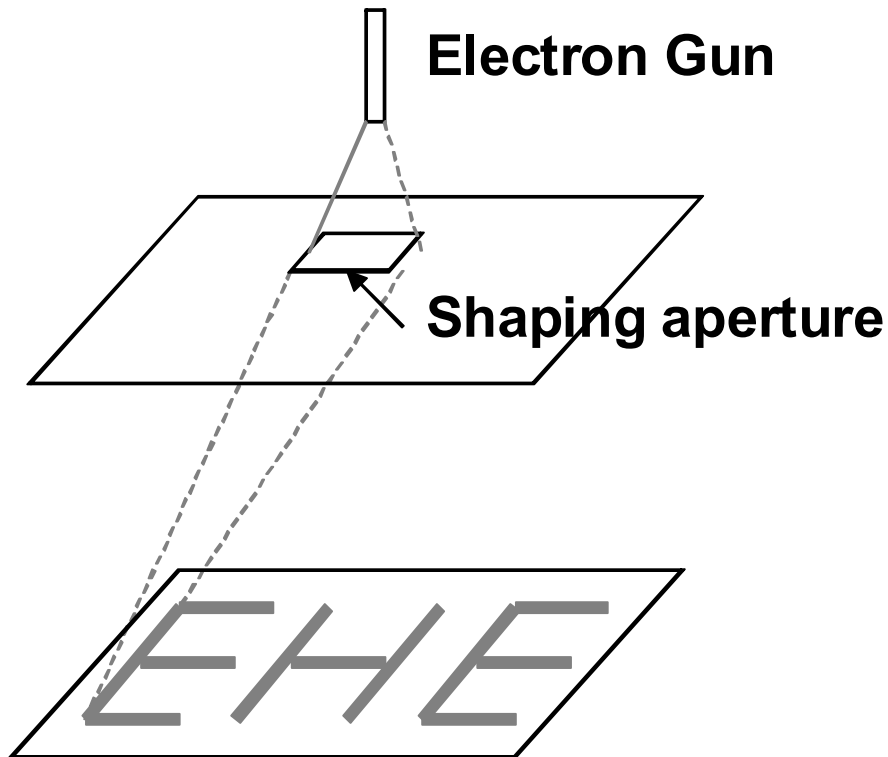
Double Patterning

Or even triple/quadruple patterning!

But mask cost will be proportionally higher!

Electron Beam Lithography

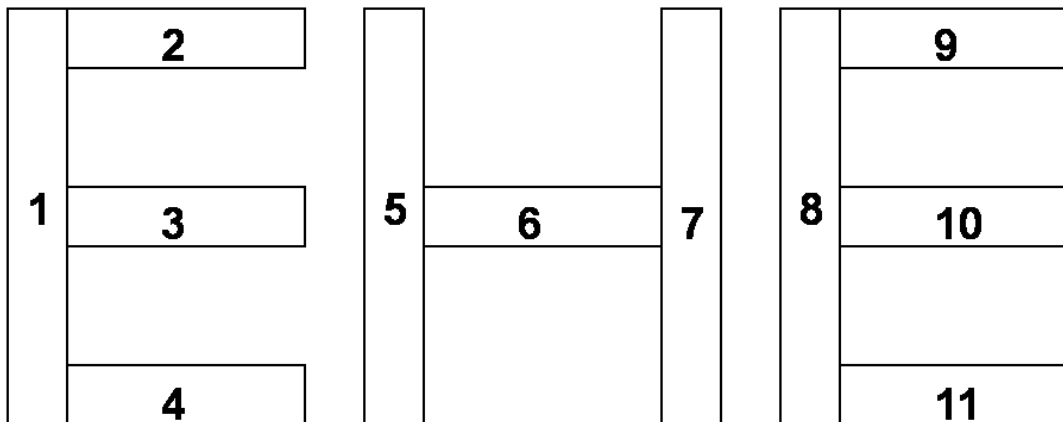
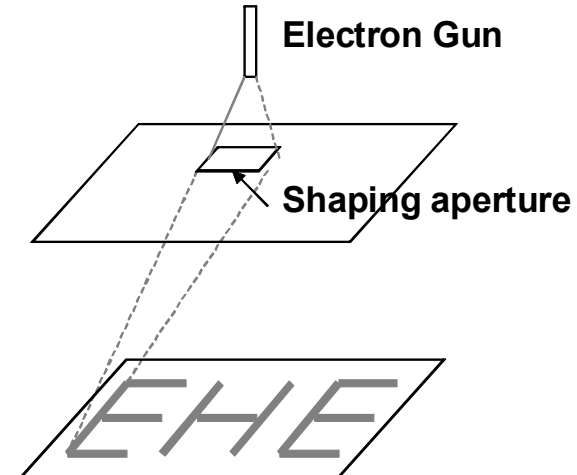
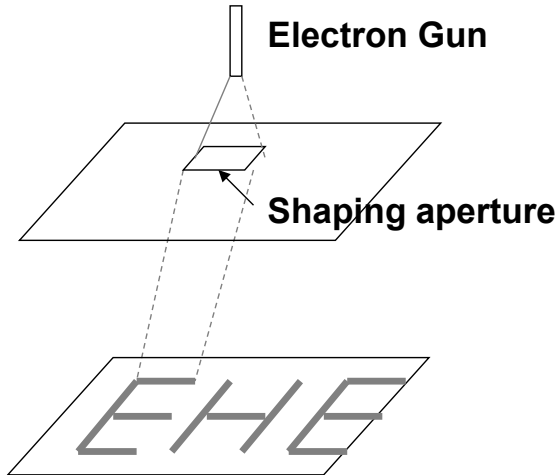
- ◆ **Maskless** technology, which shoots desired patterns directly into the silicon wafer
 - › 4x better resolution [Solid State Technology 2011]
 - › Lower cost [D2S Inc]



The biggest challenge:
Low throughput

Variable Shape Beam (VSB)

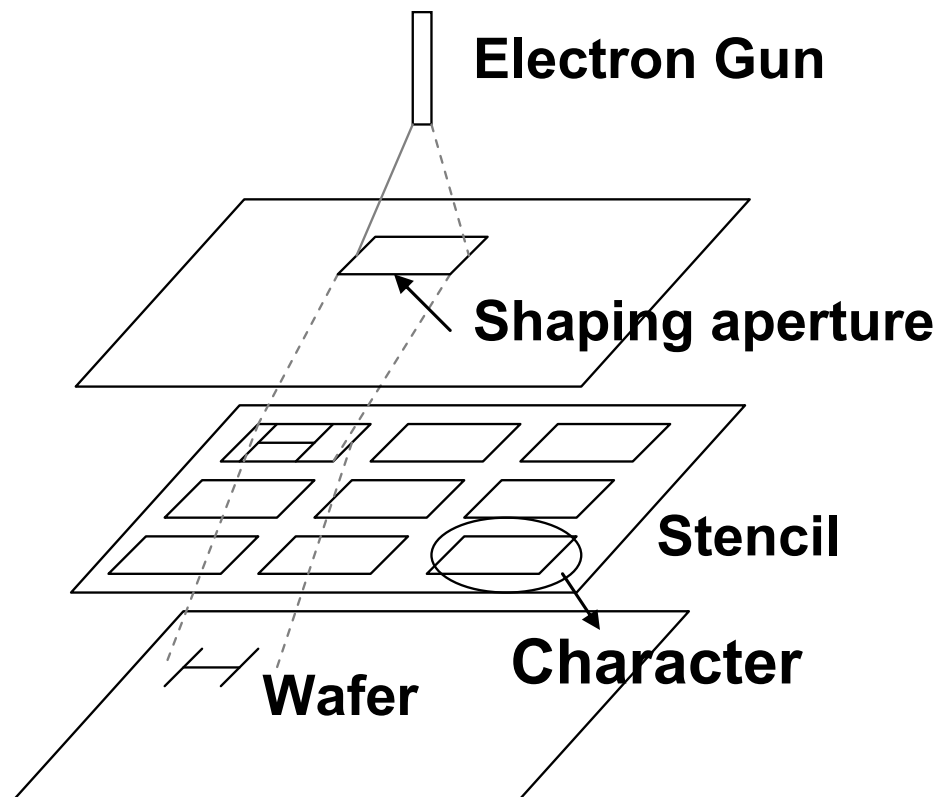
- ◆ One rectangle per shot



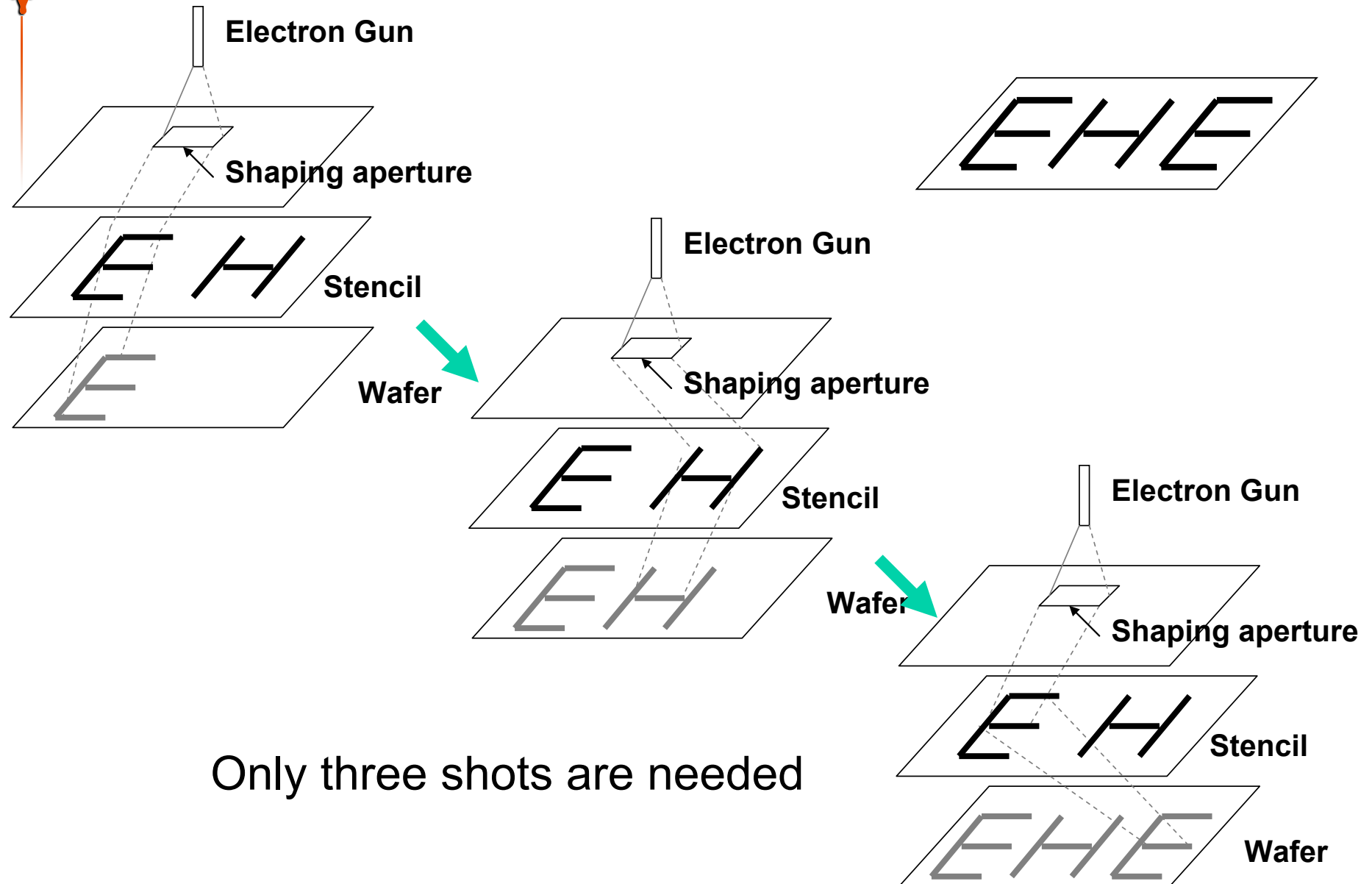
Total number of
11 shots
are needed

Character Projection (CP) Technology

- ◆ Print some complex shapes in one electronic beam shot, rather than writing multiple rectangles.

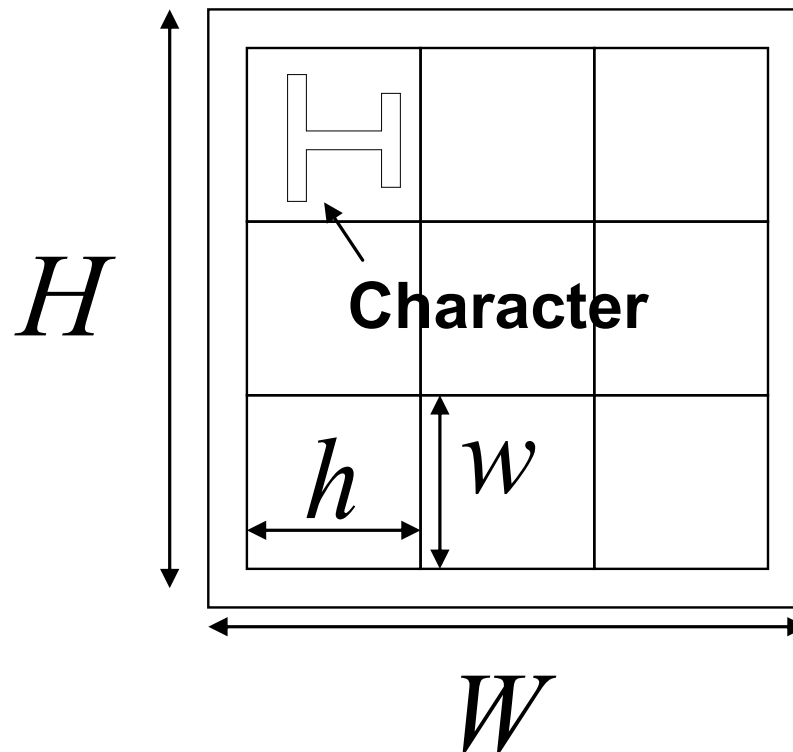


Character Projection Technology (Cont.)



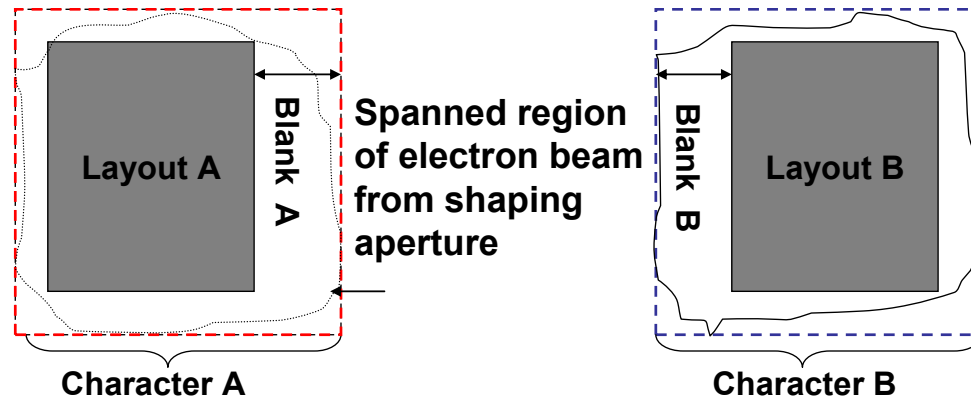
Limitation of Character Projection

- ◆ The number of characters is limited due to the area constraints of the stencil
 - › Various investigations [**Makoto et al. SPIE'06, SPIE'09**] on optimization of character selection

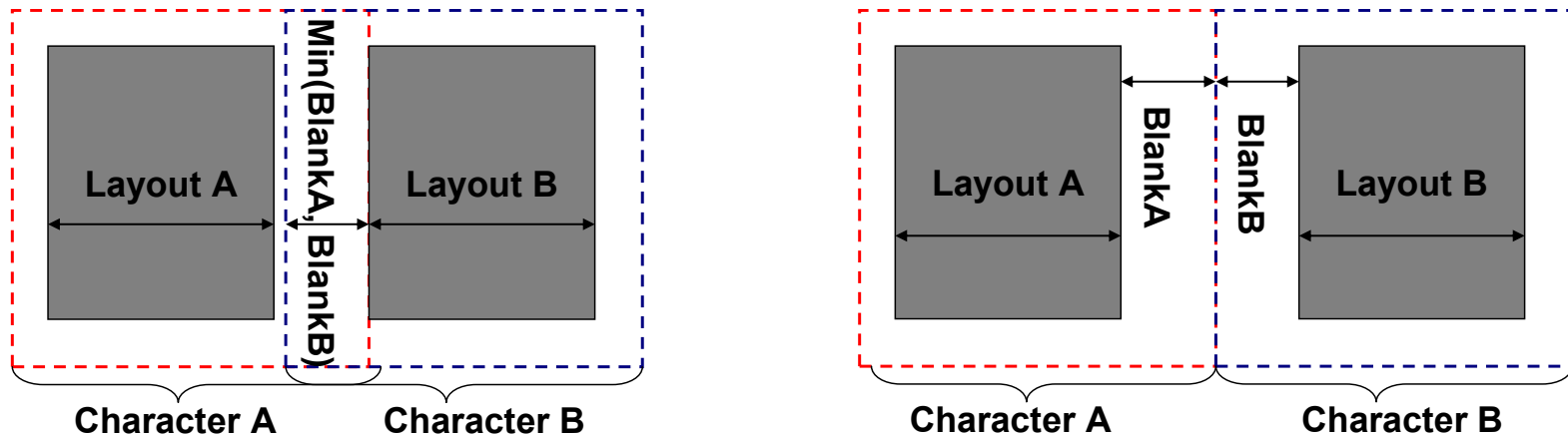


Overlapped Characters

- Blanking space is usually reserved around its enclosed rectangular circuit pattern

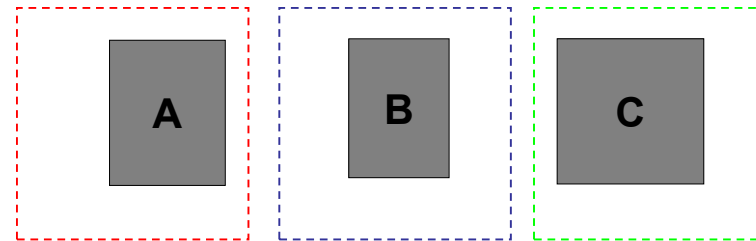


- By allowing over-lapping adjacent characters, more characters may be put on stencil [Fujimura+, 2010]

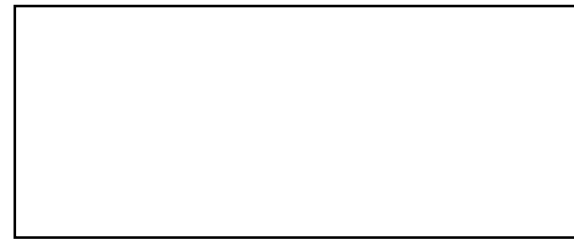


Not a Trivial Task

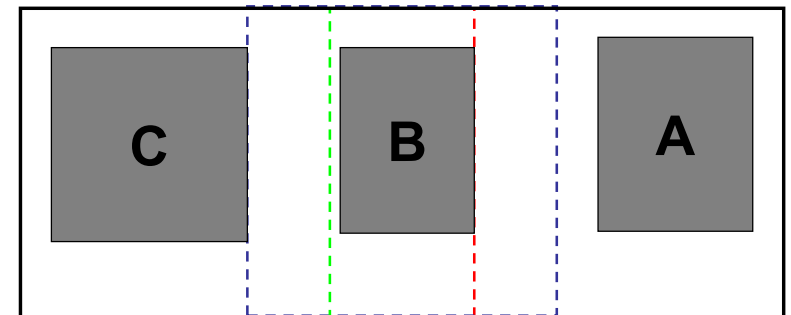
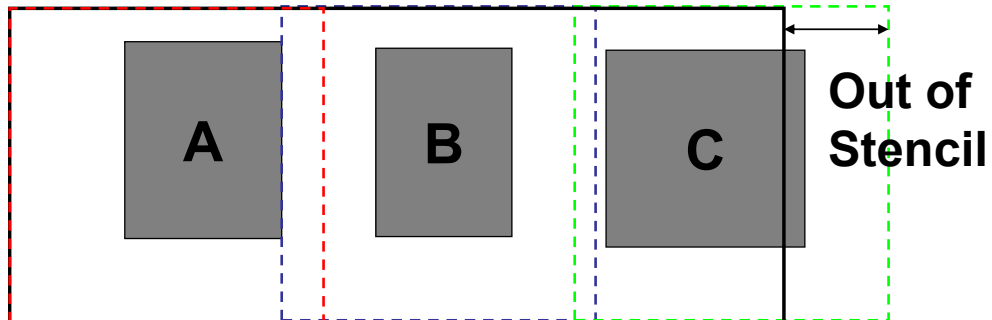
Character Candidates
to be Considered



Stencil

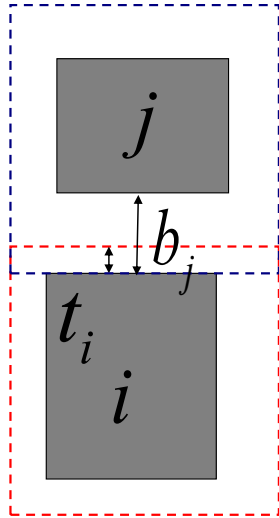


Order Matters

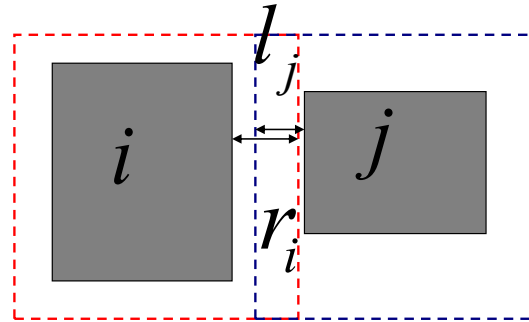


Problem Definition

- Given a set of character candidates C_C



$$o_{ij}^V = \min(t_i, b_j)$$



$$o_{ij}^H = \min(r_i, l_j)$$

Each candidate C_i appears r_i in the circuit

#shots by VSB: n_i^{VSB}

#shots by CP: n_i^{CP}

Problem Definition (Cont.)

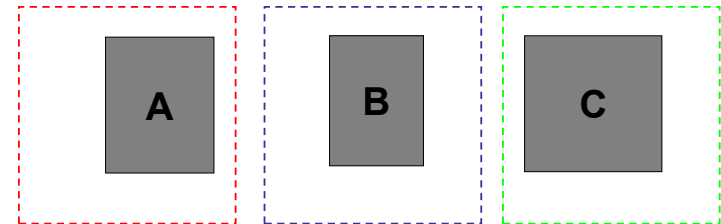
- ◆ Select a subset C_{CP} out of character candidates C_C , and place them on the stencil S

Minimize total number of shots:

$$\sum_{C_i \in C_{CP}} r_i n_i^{CP} + \sum_{C_i \in C_C \setminus C_{CP}} r_i n_i^{VSB}$$

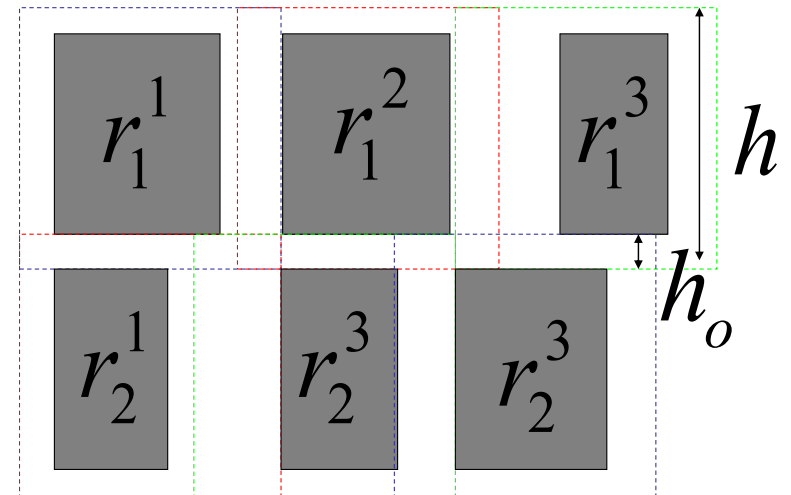
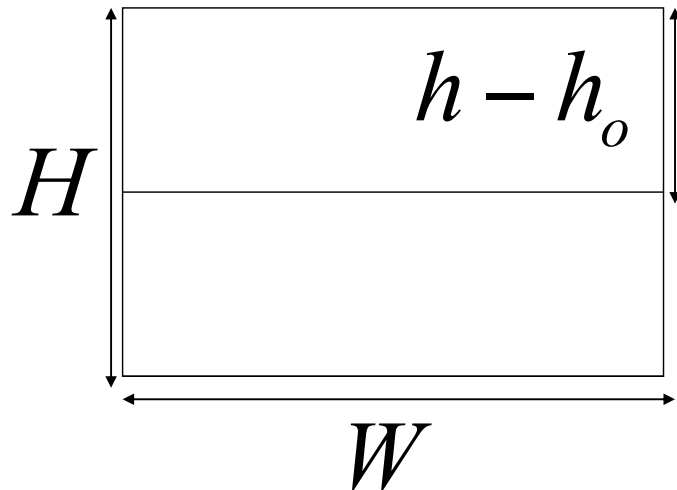
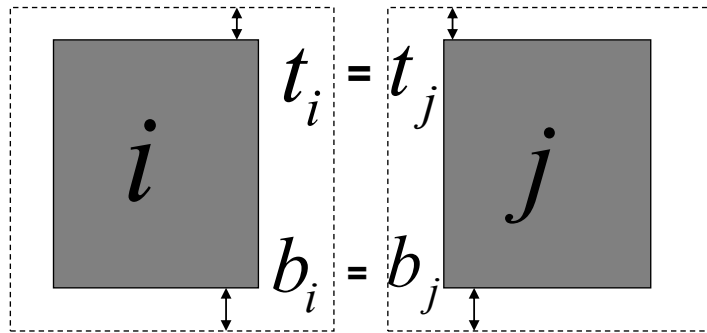
While

The placement of C_{CP} is bounded by the outline of stencil.

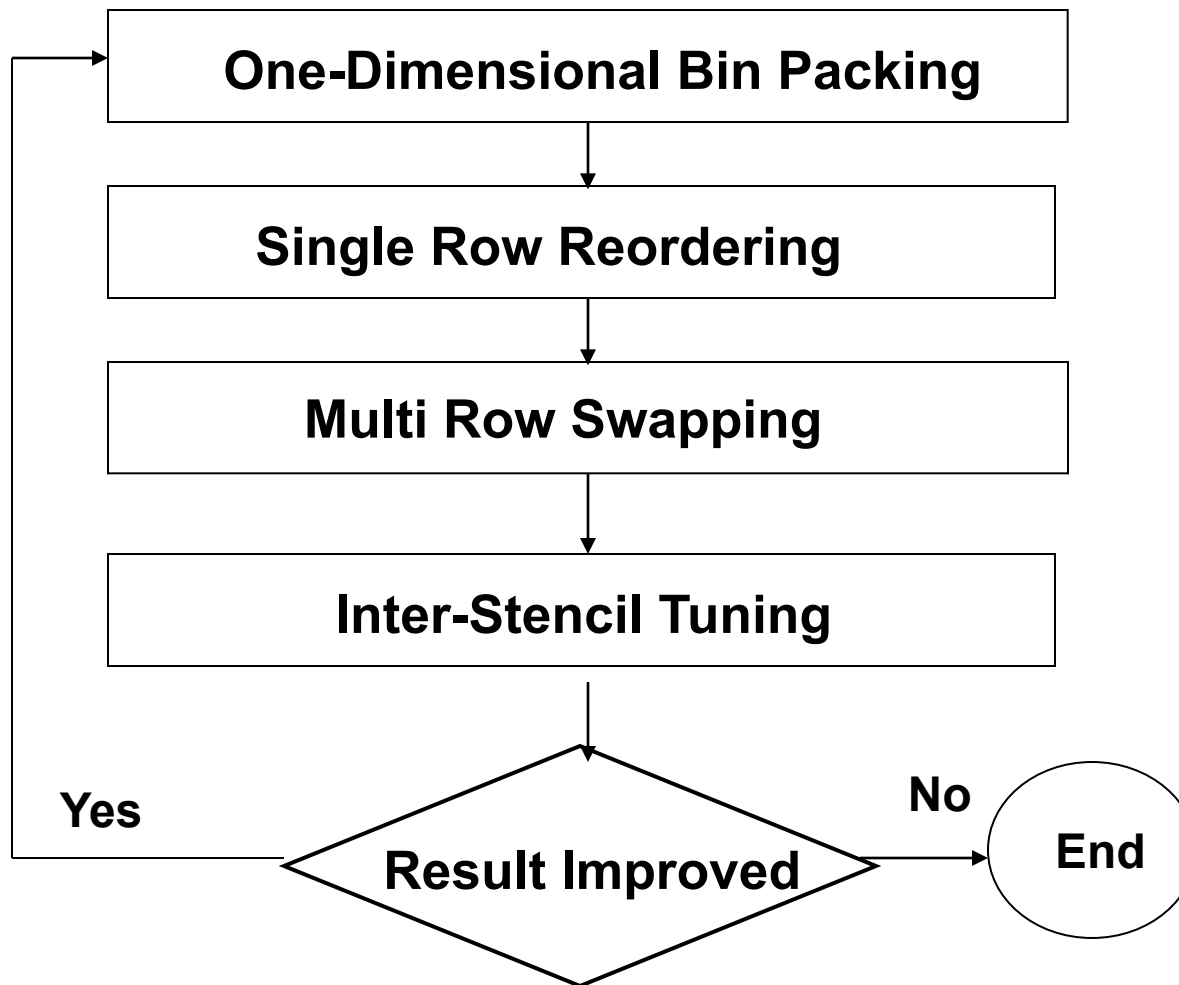


One Dimensional Problem

- ◆ The required blanking spaces on the top t and bottom b are nearly identical for all the candidates.



Optimization Flow



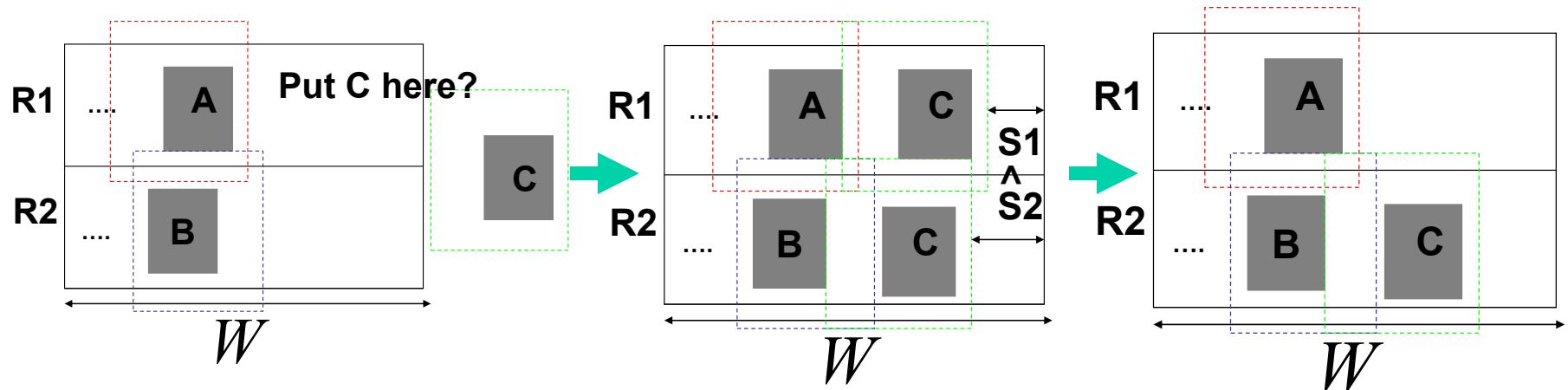
One-Dimensional Bin Packing

$$\sum_{C_i \in C_{CP}} r_i n_i^{CP} + \sum_{C_i \in C_C \setminus C_{CP}} r_i n_i^{VSB} \quad \text{Minimize}$$

$$= \sum_{C_i \in C_C} r_i n_i^{VSB} - \sum_{C_i \in C_{CP}} r_i (n_i^{VSB} - n_i^{CP})$$

Constant Maximize

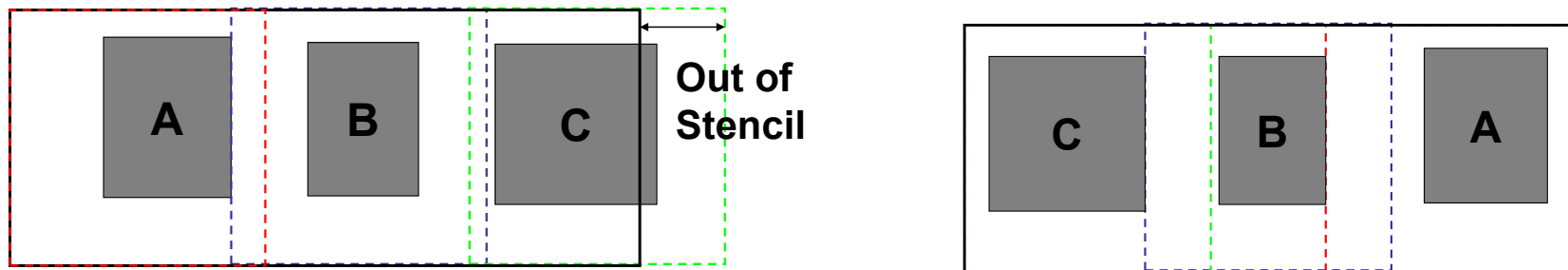
Packing by the decreasing order of $\sum_{C_i \in C_{CP}} r_i (n_i^{VSB} - n_i^{CP})$



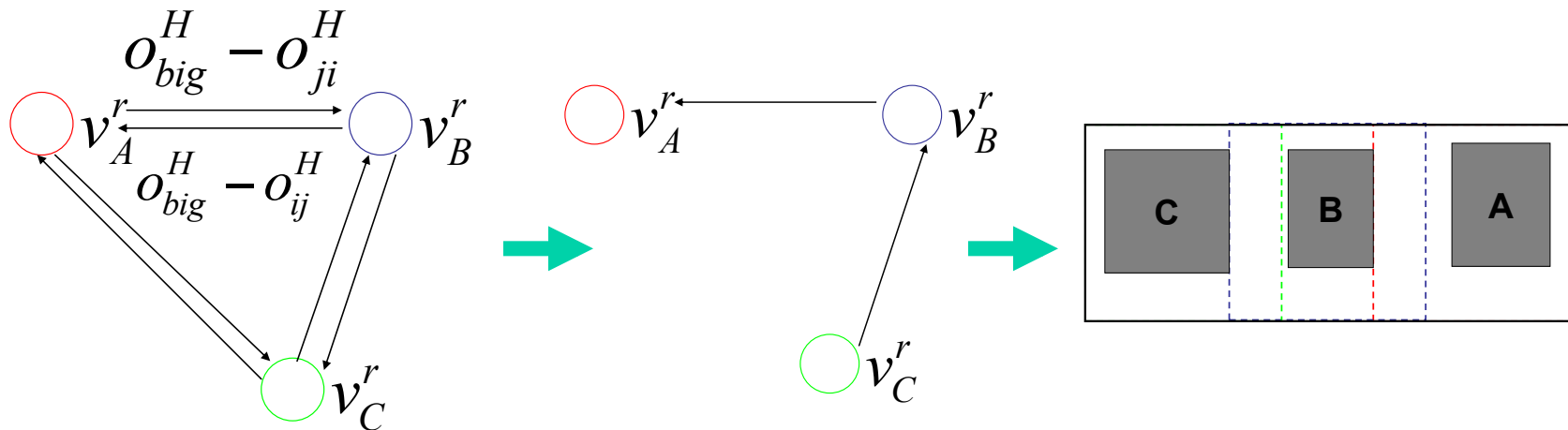
Put the candidate into the row with most blanking space left

Single Row Reordering

- Adjust the relative locations of already-placed characters in each row to shrink its occupied width and increase remaining capacity

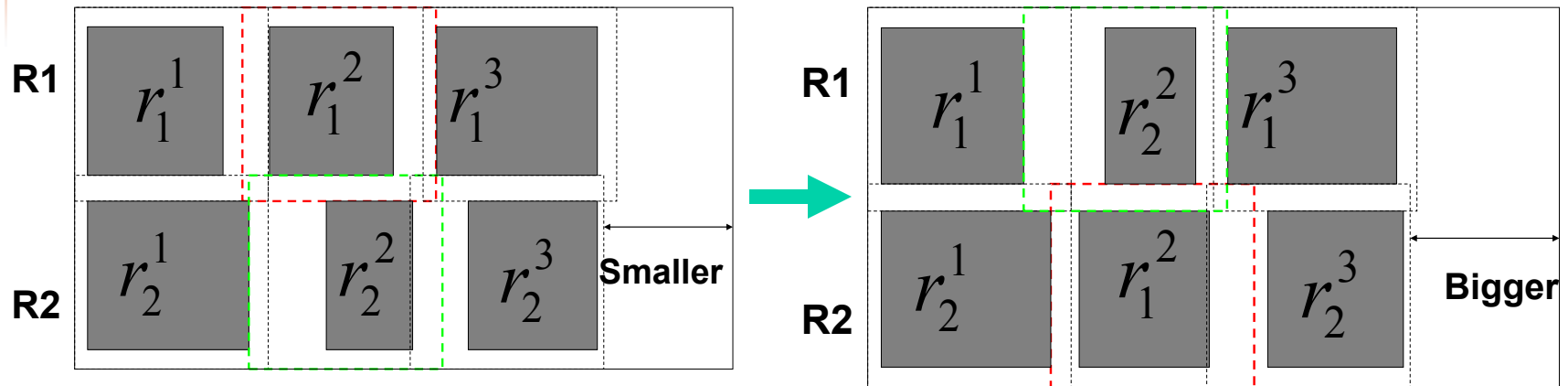


- Transform to *min-cost Hamiltonian path* problem



Multi-Row Swapping and Inter-Stencil Tuning

◆ Multi-Row Swapping



◆ Inter-Stencil Tuning

- › Exchange the placed characters with those which have not been selected

Two Dimensional Problem

- ◆ The blanking spaces of templates are non-uniform along both horizontal and vertical directions.
- ◆ Simulated Annealing Framework with Sequential Pair Representation

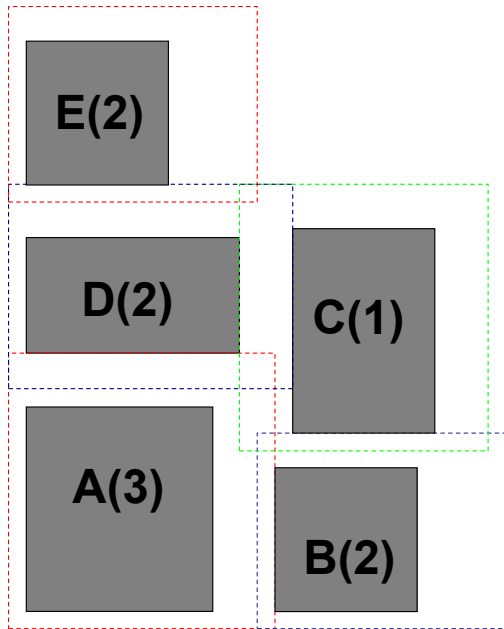
$\overline{X}, \overline{Y}$ are two permutations of characters $(c_0, c_1 \dots c_n)$

$\overline{X} = (\dots c_i \dots c_j \dots), \overline{Y} = (\dots c_i \dots c_j \dots).$ c_i is left to c_j

$\overline{X} = (\dots c_j \dots c_i \dots), \overline{Y} = (\dots c_i \dots c_j \dots).$ c_i is below c_j

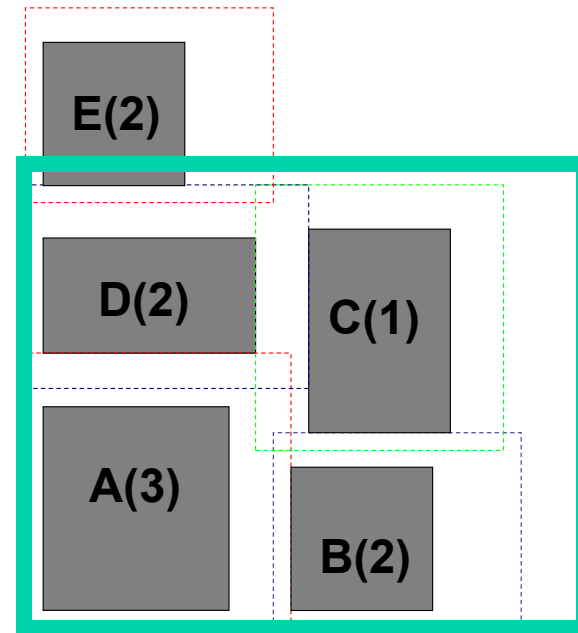
Transformation from SP to Stencil

- ◆ Transform SP to a min-area packing solution
- ◆ Pick the candidates within outline of stencil as characters



$$\overline{X} = (E D A C B)$$

$$\overline{Y} = (A B D E C)$$

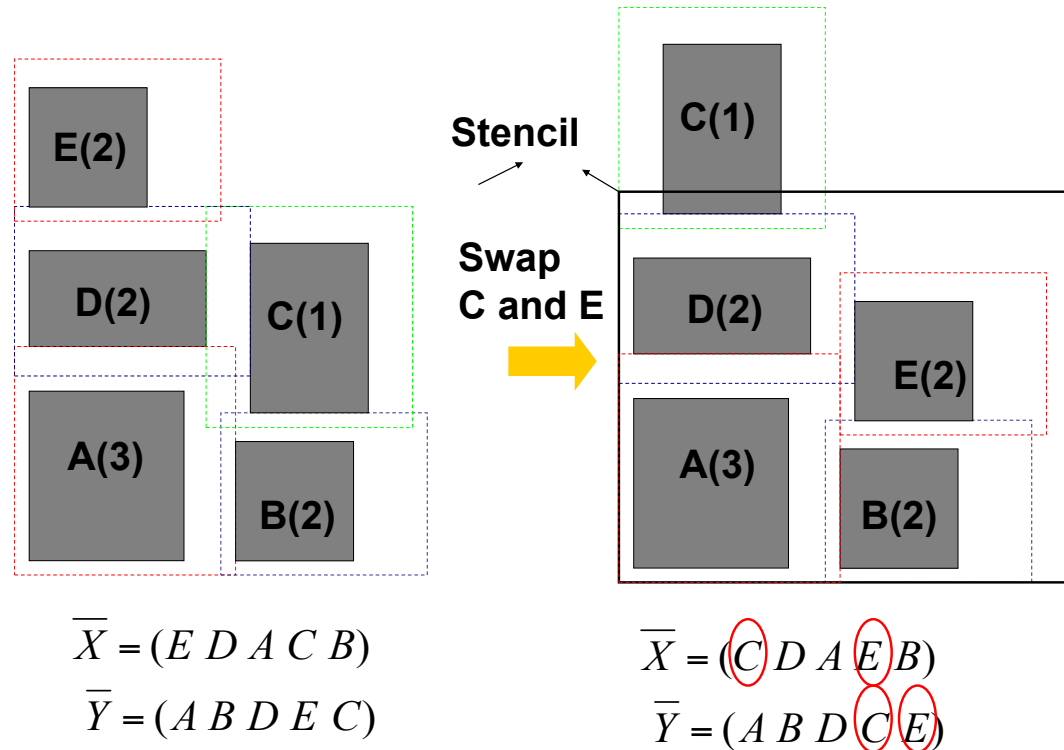


$$\overline{X} = (E D A C B)$$

$$\overline{Y} = (A B D E C)$$

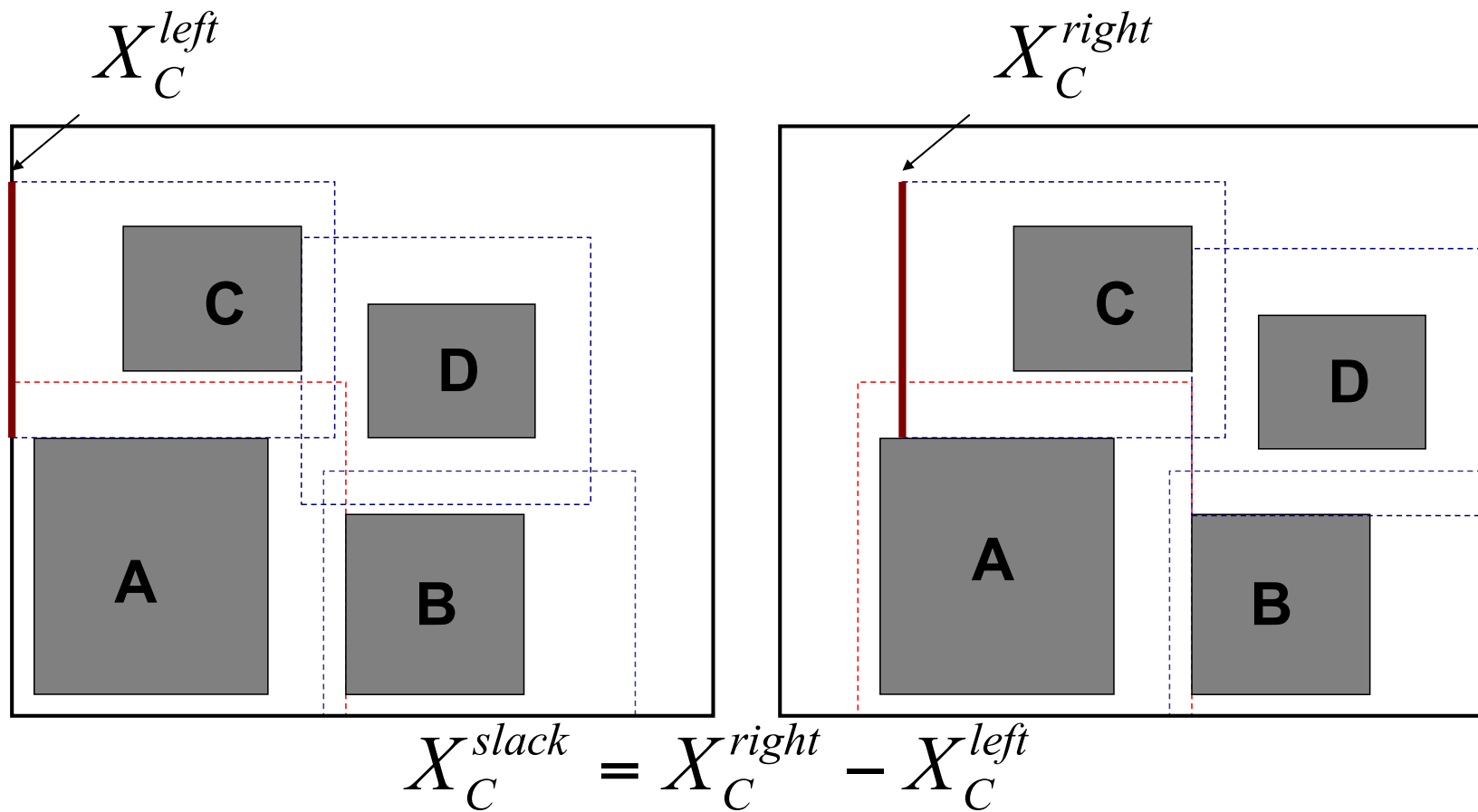
Throughput-Driven Swapping

- Try to reduce the projection time by swapping the positions of two candidates in the X & Y SP.



Slack-Base Insertion

- ◆ Make use of the concept of slack to find a good position to insert extra candidate into the stencil



Slack-Based Insertion

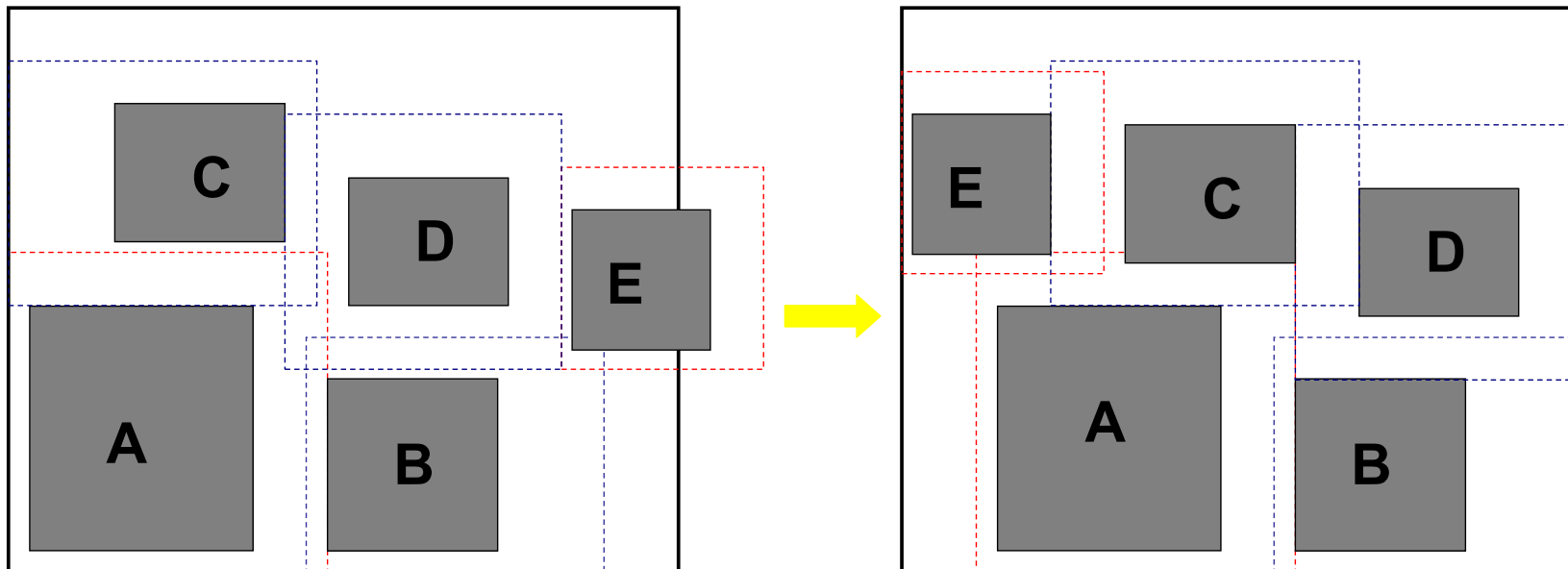
- ◆ Make use of the concept of slack to find a good position to insert extra candidate into the stencil

$$\overline{X} = (C \ A \ D \ B \ E)$$

$$\overline{Y} = (A \ C \ B \ D \ E)$$

$$\overline{X} = (\textcircled{E} \ C \ A \ D \ B)$$

$$\overline{Y} = (A \ \textcircled{E} \ C \ B \ D)$$



Experimental Setup



- ◆ Implemented in C++
- ◆ Intel 8 Core Linux, 3.0 Ghz, 32GB
- ◆ Parquet [TVLSI 2003] is adopted as SA framework
- ◆ Compare with two baseline methods
 - › ILP-based approach without overlap characters [Sugihar, SPIE 2009]
 - › Greedy bin-packing algorithm with overlap characters

Benchmark



Circuit	Character Size $\mu m \times \mu m$	Total area $1e^4 \mu m^2$	Total blanks $1e^4 \mu m^2$	Optimal area $1e^4 \mu m^2$
1D-1	3.8x3.8	1.444	0.416	1.028
1D-2	4.0x4.0	1.6	0.479	1.121
1D-3	4.2x4.2	1.764	0.514	1.25
1D-4	4.4x4.4	1.936	0.569	1.367
2D-1	3.8x3.8	1.444	0.414	1.03
2D-2	4.0x4.0	1.6	0.529	1.071
2D-3	4.2x4.2	1.764	0.662	1.102
2D-4	4.4x4.4	1.936	0.774	1.162

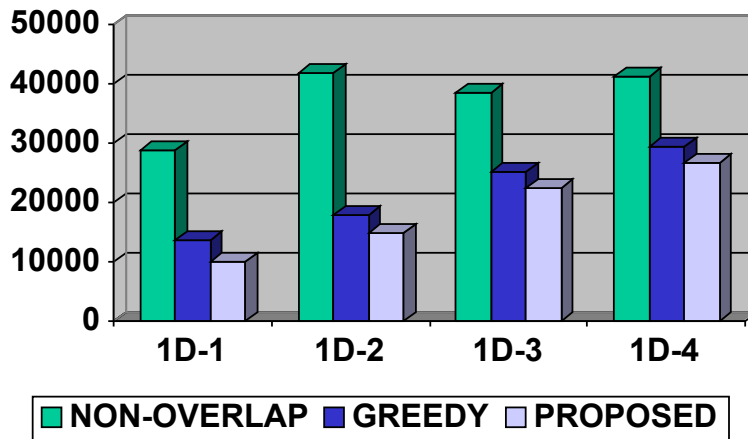
The area of stencil is $100\mu m \times 100\mu m$

1000 character candidates

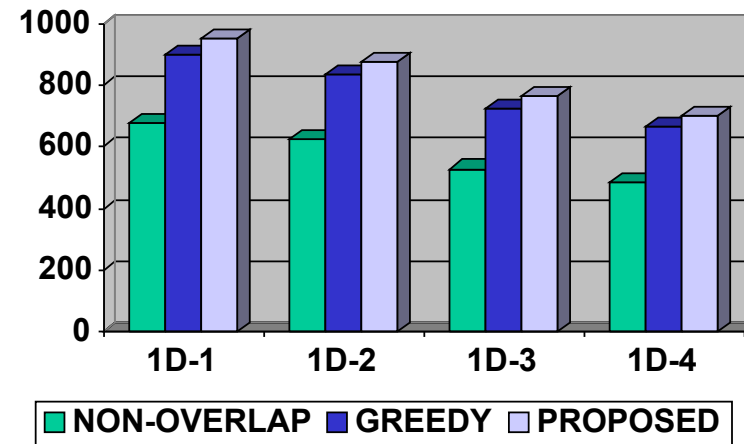
One Dimensional Stencil Design



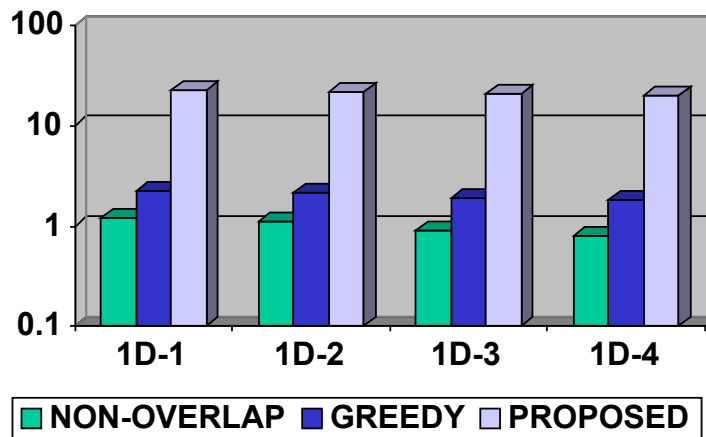
#shots (projection time)



#characters on stencil



#CPU(logscale)

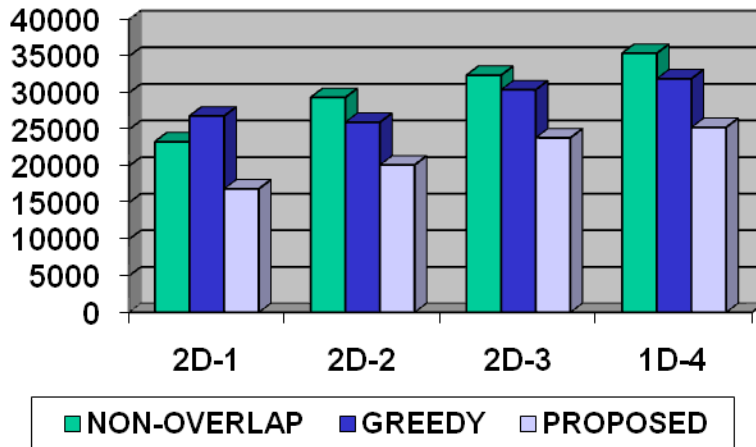


- ◆ 51%, 14% reduction on shot number over previous ILP-based approach without overlapping characters and greedy algorithm.

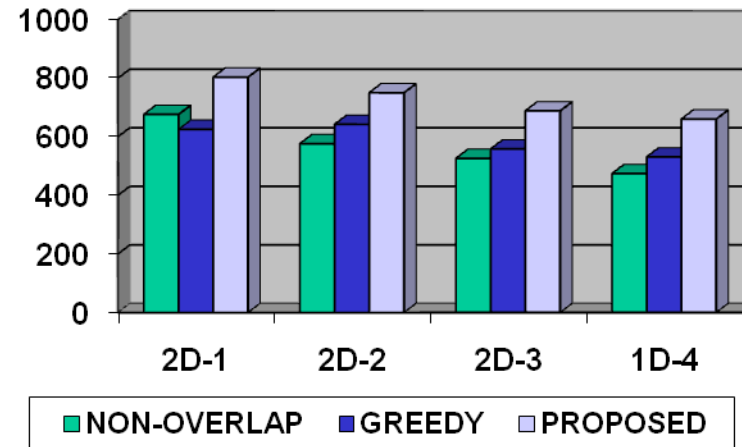
Two Dimensional Stencil Design



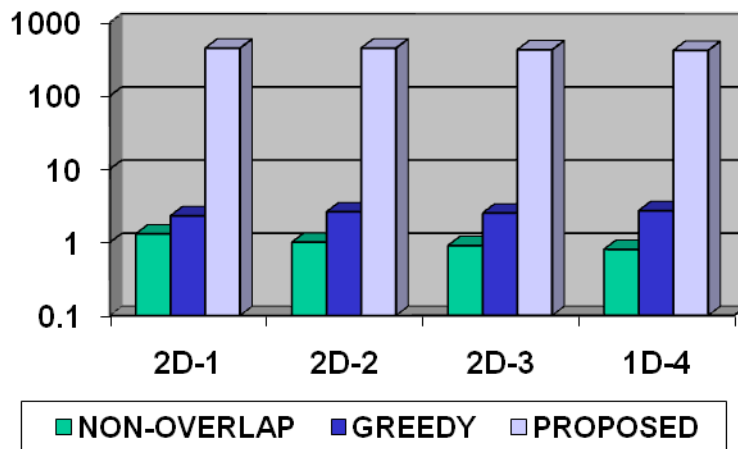
#shots (projection time)



#characters on stencil



#CPU(logscale)



- ◆ 31%, 25% reduction on shot number over previous ILP-based approach without overlapping characters and greedy algorithm.

Conclusion

- ◆ E-Beam Lithography is a promising emerging technology for better resolution and lower cost
- ◆ Low throughput is its key hurdle
- ◆ E-beam lithography stencil planning and optimization with overlapped characters
- ◆ Lots of future research opportunities on physical design and emerging lithography
 - › E-beam multi-stencil optimization problems
 - › Massive parallel e-beams/characters
 - › Double/triple patterning lithography
 - › EUV,

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- ◆ Dr. Gi-Joon Nam at IBM Austin Research Lab for helpful discussions.

Thank you!